SHARP PT100Mx0MP Series

 $(T_a=25^{\circ}C)$

Unit

V

PT100Mx0MP Series

■ Features

1. Compact and thin package

2. Surface mount type

3. 2-way mounting: top view/side view

4. Reflow soldering

5. Transparent resin: PT100MC0MP

6. Visible light cut-off resin: PT100MF0MP
Pair use with GL100MN0MP/GL100MN1MP

is recommended

■ Applications

1. Touch panels for ATM

2. Touch panels for Car navigation system

3. Touch panels for FA equipment

Parameter Symbol Rating

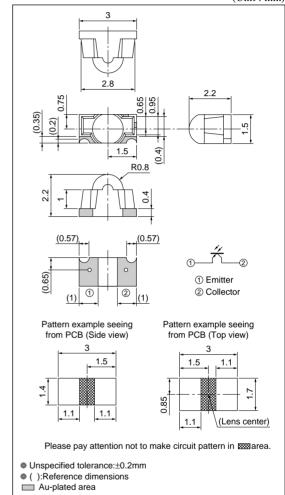
Collector-emitter voltage V_{CEO} 35

V Emitter-collector voltage V_{ECO} 6 Collector current I_{C} 20 mA P_{C} 75 mW Collector power dissipation °C Operating temperature T_{opr} -30 to +85 T_{stg} Storage temperature -40 to +95°C °C 240 *1 Soldering temperature T_{sol}

Compact, Surface Mount Type Phototransistor

■ Outline Dimensions

(Unit: mm)



^{*1} Max. 10s

■ Electro-optical Characteristics (T _a							$T_a=25^{\circ}C$
Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Collector current	PT100MC0MP	I_{C}	$^*E_e=1$ mW/cm ² , $V_{CE}=5$ V	1.7	2.9	5.1	mA
	PT100MF0MP	I_{C}	$^*E_e=1$ mW/cm ² , $V_{CE}=5$ V	1.15	2	3.45	mA
Collector dark current		I_{CEO}	$E_e = 0, V_{CE} = 20V$	_	1.0	100	nA
Collector-emitter saturation voltage		V _{CE (sat)}	$^*E_e=10 \text{mW/cm}^2, I_C=0.5 \text{mA}$	_	0.1	0.4	V
Collector-emitter breakdown voltage		BV_{CEO}	E_e =0, I_C =0.1mA	35	_	_	V
Emitter-collector breakdown voltage		BV_{ECO}	E_e =0, I_E =0.01mA	6	_	_	V
Peak sensitivity wavelength	PT100MC0MP	λ_{p}	-	_	900	_	nm
	PT100MF0MP	λ_{p}	-	_	910	_	nm
Response time	Rise time	$t_{\rm r}$	V_{CE} =2 V , I_{C} =2 mA , R_{L} =100 Ω	_	5.0	_	μs
	Fall time	$t_{\rm f}$	V_{CE} =2 V , I_{C} =2 mA , R_{L} =100 Ω	_	6.0	_	μs
Half intensity angle		Δθ		_	±15	_	۰

^{*} E.: Irradiance by CIE standard light source A (tungsten lamp)

Fig.1 Collector Power Dissipation vs. **Ambient Temperature**

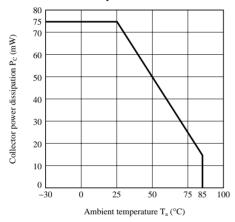


Fig.3 Relative Collector Current vs. Ambient **Temperature**

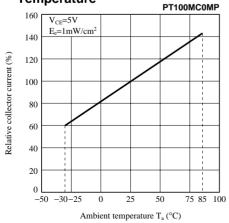


Fig.2 Collector Dark Current vs. Ambient **Temperature**

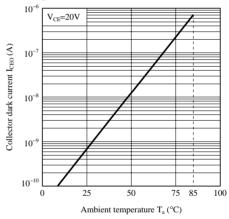


Fig.4 Relative Collector Current vs. Ambient **Temperature**

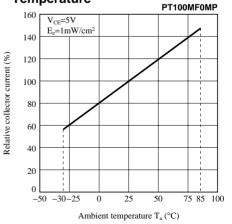


Fig.5 Collector Current vs. Irradiance

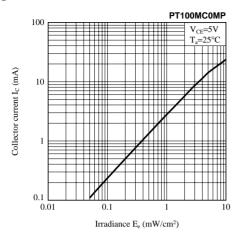


Fig.7 Collector Current vs. Collector-emitter Voltage

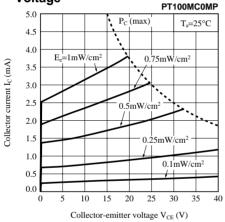


Fig.9 Relative Sensitivity vs. Wavelength (Typical Value)

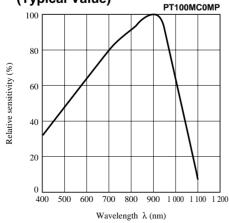


Fig.6 Collector Current vs. Irradiance

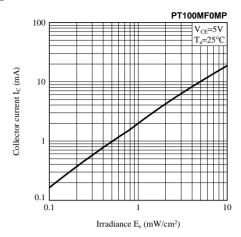


Fig.8 Collector Current vs. Collector-emitter Voltage

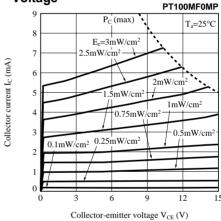


Fig.10 Relative Sensitivity vs. Wavelength

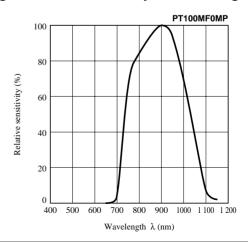


Fig.11 Radiation Diagram

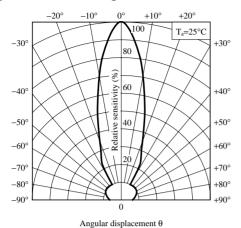


Fig.12 Collector-emitter Saturation Voltage vs. Irradiance

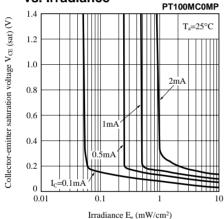


Fig.14 Relative Output vs. Distance To Detector

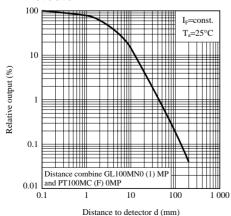


Fig.13 Collector-emitter Saturation Voltage vs. Irradiance

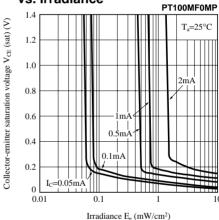
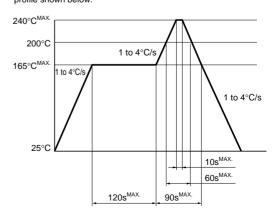


Fig.15 Reflow Soldering

Only one time soldering is recommended within the temperature profile shown below.



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